

**Search Notes**

Application/Control No.

10/645,412

Examiner

Patricia Leith

Applicant(s)/Patent under  
Reexamination

HON ET AL.

Art Unit

1655

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
updated EAST:JPO,EPO,DERWENT,USPATF ULL,USPGPUBS,OCRBKFILE	2/2/2006	PL